## Message from Steering Committee Chairs

After two consecutive years at NIST (the National Institute of Standards and Technology) in Gaithersburg, Maryland, SERE 2014 is the first time that the conference is held in the west coast of the U.S. Welcome to San Francisco – a city that has made a significant impact on our society: the 1848 gold rush, the 1990s dot-com boom, and the high tech in Silicon Valley. Of course, let us not forget the Golden Gate Bridge, Alcatraz Island, and world renowned institutions – Stanford and U.C. Berkeley.

This year is the eighth annual meeting for SERE (International Conference on Software Security and Reliability), where SE stands for security and RE for reliability. With its increasing use in many large, complicated systems such as in transportation, medicine, finance, and nuclear power generation, software has become an absolute factor in our everyday lives. Assuring the secure and reliable operation of these systems is of the highest priority, since a failure of such systems can lead to a significant financial loss or even human casualties. In response to this emerging trend, SERE 2014 has a special theme on *Software Quality Assurance*.

In addition to the main conference, there are four co-located workshops focusing on carefully selected topics, yet still closely related to the theme, to help the conference provide an even more attractive platform for researchers, practitioners, policy makers, and students to exchange ideas and results, share experiences and suggestions, and discuss solutions and practices appropriate for their challenges at work.

Accepted papers will appear in the proceedings or companion published by the IEEE Conference Publishing Services. They will also be submitted for inclusion into the IEEE Xplore digital library and to all of the A&I (abstracting and indexing) partners (such as the EI Compendex). Moreover, authors of selected best papers will be invited to submit an extended version to a special section of the *IEEE Transactions on Reliability* (T-Rel).

We give special thanks to Professor Wen-Guey Tzeng (Program Chair), Professors Yunwei Dong, Shih-Kun Huang, Fu-Hau Hsu, Yu-Sung Wu, and Donghui Guo (Workshop Organizers) for their leadership in the organization of the conference, all the Program Committee members and reviewers for evaluating and selecting papers, and providing valuable comments to help authors further improve the quality of their work, and especially the authors for sharing their innovative ideas and advanced research with all the conference attendees. Without their contribution, the impact of the conference would be diminished.

We extend our appreciation to Professor Rui Maranhao (Workshop Chair), Professor Raul Santelices (Student Doctoral Program Chair), Professor Sudipto Ghosh (Publicity Chair), Professor Yu-Lun Huang (Publication Chair), and Professor Junhua Ding (Registration Chair) for their excellent assistance in organizing the conference.

Thanks also go to Ruizhi Gao, Shou-Yu Lee, Yihao Li, and Xuelin Li at the University of Texas at Dallas for designing, implementing, and maintaining the conference website, and other organizational tasks.

We hope that you enjoy the technical and social events we have prepared for you. We also look forward to your feedback and continuous support to make the conference more successful year after year.



Sam Keene IEEE Reliability Society



W. Eric Wong University of Texas at Dallas, USA